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| Notice of References Cited | Application/Control No. 09/683,002 | Applicant(s)/Patent Under Reexamination BASTIAENS ET AL. | |
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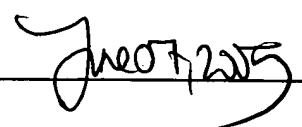
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Application/Control No.

09/683,002

Applicant(s)/Patent Under
Re examination
BASTIAENS ET AL.

Examiner

Rip A. Le

Art Unit

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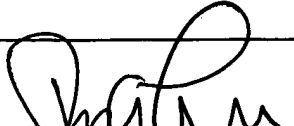
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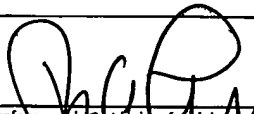
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